Abstracts

Ill conditioning in self-heating FET models

S.A. Maas. "Ill conditioning in self-heating FET models." 2002 Microwave and Wireless Components Letters 12.3 (Mar. 2002 [MWCL]): 88-89.

This paper shows that the introduction of self heating effects into a FET model can cause severe ill conditioning in nonlinear circuit simulators. Depending on the parameter values of the model, the solutions can be indistinct, multiple, or even nonexistent. The result is poor convergence in nonlinear simulations using such models.

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